## **PHOTOVOLTAIC – MATERIALS, CELLS AND DEVICES**

	CHALLENGES	SOLUTIONS
Chemical Analysis /Spectroscopy	<ul> <li>Detection and quantification of impurities</li> <li>Encapsulant studies</li> <li>Characterise encapsulates, degradation of encapsulates</li> <li>Chemical and thermal analysis of organic material</li> <li>Qualitative chemical measurements</li> <li>Optical transmission/reflection</li> <li>Surface height/roughness; manufacturing accuracy</li> </ul>	<ul> <li>Fourier Transform Infrared Analysis</li> <li>Gel Permeation Chromatography</li> <li>Differential Scanning Calorimetry</li> <li>Thermal Gravimetric Analysis</li> <li>Wet Chemical Analysis</li> <li>UV-Visible-IR optics spectrometer</li> <li>Atomic Force Microscope</li> </ul>
Device / Internal Analysis	<ul> <li>Visible inspection of defects/failures</li> <li>Large area cross section cutting, large area patterning</li> <li>Removal of organic compounds/surface cleaning</li> <li>Device characterisation</li> <li>Long duration testing, calibrated solar cell at AM1.5G</li> <li>Cross sectional analysis/imaging of &lt;100nm defects</li> <li>Multiple low noise electrical measurements</li> <li>Depth profiling, identifying contaminants/impurities</li> <li>Surface cleaning, surface mapping of elements</li> </ul>	<ul> <li>High Magnification Optical Microscopes</li> <li>Laser Isolation/patterning/cleaning equipment</li> <li>Plasma Etcher</li> <li>Probe Stations for Device Characterisation</li> <li>Class 'A' solar simulator and light soakers</li> <li>Focussed Ion Beam/SEM</li> <li>Switch Matrix</li> <li>TOF-SIMS</li> </ul>
Electrical / Electronic Test	<ul> <li>Low noise IV measurements</li> <li>Series/parallel resistance calculation, capacitance, diode factor, minority carrier lifetime, acceptor impurities, density and depletion layer charge density</li> <li>Automated, multiple low noise electrical measurements</li> </ul>	<ul> <li>✓ Agilent Femto-Amp resolution parameter analysers</li> <li>✓ RLC bridges impedance measurements</li> <li>✓ Automated Test Equipment</li> </ul>
Environmental Testing	<ul> <li>Outdoor monitoring trials</li> <li>Outdoor monitoring trials</li> <li>Accelerated tests</li> <li>Full module testing</li> <li>Accelerated weathering &amp; UV degradation</li> <li>Testing for delamination, yellowing, cracking, colour cx</li> </ul>	<ul> <li>Outdoor test rigs for solar modules</li> <li>Weather station and irradiance sensor</li> <li>Environmental Chambers</li> <li>Light soaking</li> <li>AM1.5G solar simulator</li> </ul>
Electron Microscopy / Surface Analysis	<ul> <li>External visual inspection for cracks/failures/defects</li> <li>Elemental analysis</li> <li>Surface roughness of optical coatings</li> <li>Metal corrosion</li> <li>Identification of phase</li> <li>Optical constants, non-destructive change to optical properties</li> <li>Cross sectional analysis, failure analysis</li> </ul>	<ul> <li>Field Emission Scanning Electron Microscopy</li> <li>Energy Dispersive X-ray Spectroscopy</li> <li>Atomic Force Microscopy</li> <li>Kelvin probe microscopy</li> <li>Kelvin probe microscopy</li> <li>X-ray Diffraction</li> <li>Ellipsometry</li> <li>Focussed Ion Beam (via partner)</li> </ul>
Materials Processing	<ul> <li>Solar cell fabrication</li> <li>Vacuum annealing solar cells</li> <li>PV fabrication (Active layers/contacts)</li> <li>Electrical contact/dielectric/AR coating</li> <li>Electrical contact/dielectric/AR coating</li> <li>Step heights</li> <li>Calibration of TOF-Sims</li> </ul>	<ul> <li>Vacuum Furnaces up to 600° C</li> <li>Photolithography</li> <li>3-source sputter coater</li> <li>Electron Beam deposition</li> <li>Thermal evaporation of metals/organic materials</li> <li>Class 1000 cleanroom</li> <li>Atomic Force Microscopy</li> </ul>
Non- Destructive Analysis	<ul> <li>Surface roughness of optical coatings</li> <li>Metal corrosion</li> <li>Identification of phase</li> </ul>	<ul> <li>✓ Probe station, surface analysis equipment - AFM</li> <li>✓ Probe station, surface analysis equipment - KFM</li> <li>✓ Probe station, surface analysis equipment - XRD</li> </ul>
Electrostatic Testing	<ul> <li>Surface resistivity measurement</li> <li>Charge Decay monitoring</li> <li>Field Meter measurement</li> <li>Conduction to ground monitoring</li> <li>Powder coating test set</li> </ul>	<ul> <li>Surface resistivity measurement</li> <li>Charge Decay monitoring</li> <li>Field Meter measurement</li> <li>Conduction to ground monitoring</li> <li>Powder coating test set</li> </ul>
oftware	<ul> <li>Estimations of solar farm performance for fault identification</li> </ul>	<ul> <li>✓ Specialised FMEA software package</li> <li>✓ PV Sol installer software</li> <li>✓ High Performance Computing access</li> </ul>